

integrated into the final module solutions are based on the aluminum gallium nitride (AlGaN)/gallium nitride (GaN) heterostructure fabricated into both diodes and transistors. The transistor is a high-electron-mobility transistor. The cross section of the material structure and the device design of a typical device is shown in the figure. The current is carried by a two-dimensional electron gas

possessing high electron mobility formed at the AlGaN/GaN interface to neutralize the positive charge that exists at the interface due to the polarization difference between the AlGaN and the GaN. This polarization difference (a materials property) increases almost linearly with Al composition enabling a simple tailoring of the electron density by material composition without the need for doping. This results in extremely high electron mobility, in excess of $2000 \text{ cm}^2\text{V}^{-1}\text{s}^{-1}$ with charge densities typically around $1 \times 10^{13}\text{cm}^{-2}$. The resulting low resistance of the channel coupled by the high breakdown voltage enabled by the high breakdown field strength ($>3 \times 10^6\text{cm}^{-1}$; 10 times that of silicon because of the larger bond strength and bandgap of GaN) results in exceptionally high efficiencies of over

99.2% in converting 200 V dc to 400 V dc and 98.5% in a photovoltaic inverter both in the range of a kW of power at a high frequency of 100 kHz. These results demonstrate that the promise of high-efficiency GaN-based power conversion is now becoming a reality and the market penetration will continue to increase as the technology matures and the advantages of low-loss and small form factor drive new designs.

Opportunities

Transphorm is currently working with and continues to seek to work with companies as customer-partners to help develop new solutions together by combining Transphorm's expertise with that of the customer. The company also works with universities that have an established expertise in power conversion so that the capabilities of the technology can be studied in innovative new architectures and applications including advanced packaging.

Source: Carl Blake, VP Marketing, Transphorm Inc., 115 Castilian Drive, Goleta, CA 93117, USA; tel. 805-456-1300 ext.116; fax 805-968-1985; email cblake@transphormusa.com; and www.transphormusa.com.

Seeing more clearly at the nanoscale

The pitch

Recent advancements in a wide range of instrumentation including high-resolution electron and optical microscopes, chemical analyzers, and spectroscopes allow researchers to see and manipulate matter with unprecedented precision and accuracy. However, despite large investments by universities, government facilities, and industry in these instruments and capabilities, sample preparation and poor sample quality continue to impede characterization accuracy, reproducibility, and throughput. Poor sample preparation creates artifacts such as aggregation or sample damage that introduce uncertainty in data and analysis and that often require multiple samples for a single quality data point or image.

Dune Sciences' patent-pending SMART grids™ functionalized characterization substrates address this problem by imparting greater control over specimen dispersion, coverage, uniformity, and repeatability. In addition, SMART grids facilitate correlated analysis using multiple analytical instruments on the same sample to streamline the characterization process. SMART grids and related characterization products reduce the time and money required for sample preparation and analysis by 50% or more in many cases and result in increased confidence in reporting results due to improved data quality.

The total market for analytical instruments for nanoscale characterization including electron, ion, atomic

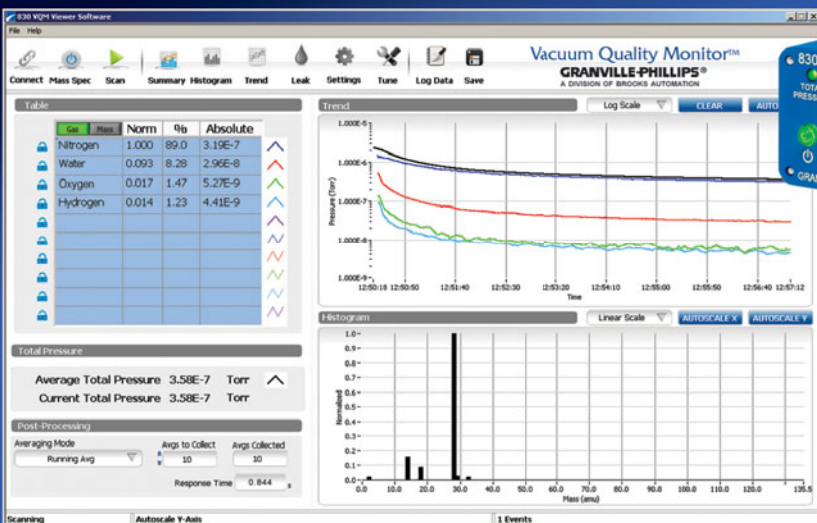
force and optical microscopes, surface/chemical analyzers, and other equipment exceeded \$3 billion in 2009. Dune Sciences' products and services leverage the value of these instruments by maximizing their utility to meet a growing list of application needs in both materials science and life science. In materials science SMART grids standardize sample preparation and provide superior data quality for a wide range of materials for accurate determination of their physical properties (e.g., size and shape), for process optimization and materials integration, manufacturing quality control, failure analysis, and environmental monitoring of nanomaterials to determine their fate and transport. In the life sciences they enhance sample specificity and reproducibility for higher throughput analysis in structural biology, toxicology, pharmaceutical research, and quality control and diagnostic screening (i.e., viral/bacterial).

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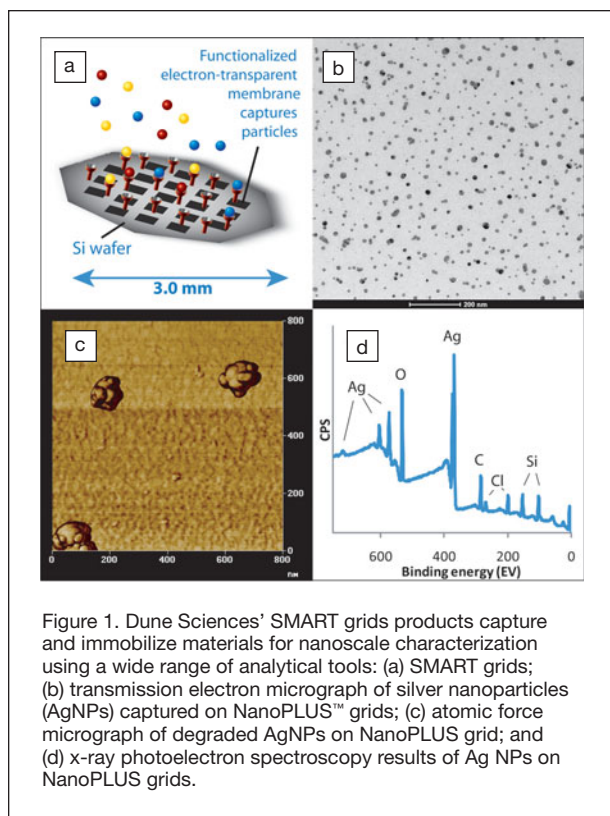


Figure 1. Dune Sciences' SMART grids products capture and immobilize materials for nanoscale characterization using a wide range of analytical tools: (a) SMART grids; (b) transmission electron micrograph of silver nanoparticles (AgNPs) captured on NanoPLUS™ grids; (c) atomic force micrograph of degraded AgNPs on NanoPLUS grid; and (d) x-ray photoelectron spectroscopy results of Ag NPs on NanoPLUS grids.

The technology

SMART grids are unique substrates for nanoscale characterization because, unlike other related products, they have active functionalized surfaces that attract and capture and immobilize ma-

terials on the surface using electrostatic and/or chemical interactions (Figure 1a). This feature not only improves sample quality and reduces artifacts for routine sample analysis than is otherwise available, but also markedly changes the role of the characterization substrate from a passive physical support to an active participant in characterization experiments. At the core of this product line are micromachined 3-mm diameter silicon substrates with ultraflat functionalized electron- and optically transparent SiO_2 and low-stress Si_3N_4 membrane windows (Figure 1a).

SMART grids have thermal, chemical, and physical stability that accommodate a wide range of sample preparation and post-deposition processing conditions. In addition, their rigid structure and grid geometry allow for analyzing the same sample using a suite of analytical methods (Figure 1b,c,d), optical microscopy, and other nanoscale techniques to directly corre-

late structure and function data.

The most recent addition to the SMART grids product line are C-SMART functionalized carbon grids that are tuned for low-contrast materials such as biological molecules and applications including cryoelectron microscopy and tomography. SMART grids are available with various surface chemistries and as sample preparation kits for a wide range of materials and application needs.

An emerging challenge in the commercialization of nanotechnology-enabled products are new regulatory policies being established to minimize any negative impacts on human health and the environment. Dune Sciences' products and services make it possible to investigate nanomaterials under quasi-real-world environmental conditions to determine their fate and more accurately assess their risks.

Opportunities

Dune Sciences is seeking partnerships and collaborations to develop and promote new applications for their products in research and industry.

Source: John M. Miller, President, Dune Sciences, Inc., 1900 Millrace Drive, Eugene, OR 97403, USA tel. 541-359-4710; fax 541-550-1613; email smartgrids@dunesciences.com; and www.dunesciences.com.

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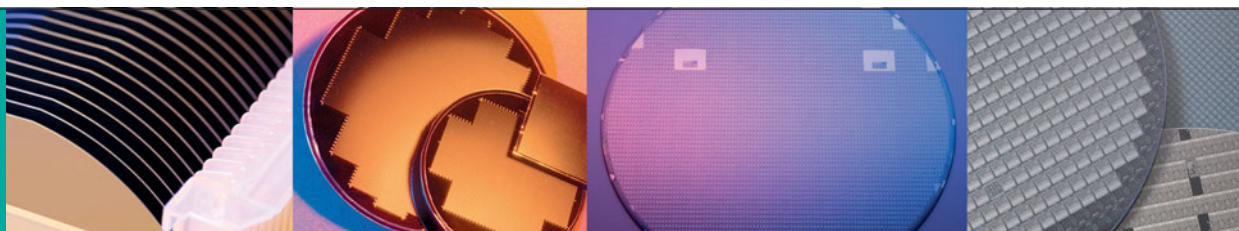
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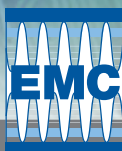
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Scientific Program

The three-day conference will feature oral and poster presentations covering 31 topics in four categories:

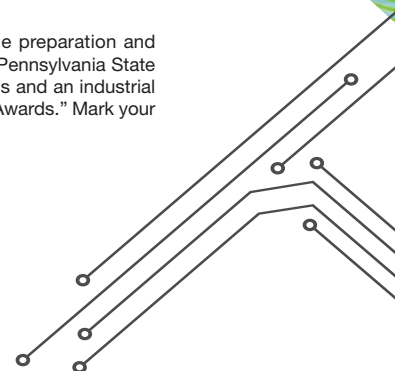
Energy Conversion and Storage Materials
Wide Bandgap Materials
Enabling Technologies
Nanoscale Science and Technology in Materials

Conference Venue

Pennsylvania State University (PSU) is consistently ranked one of the leading universities for materials science and engineering by the National Science Foundation, making it an ideal conference location. The campus is nestled among the beautiful Pennsylvania countryside, and is rich with trails to explore. Enjoy the family-friendly atmosphere with weekly arts festivals, fine boutiques and historic sites. Take a trip to the famous Penn State Creamery, the largest university creamery in the U.S., for one of their 100 flavors of ice cream. From sightseeing to action-packed adventures, you won't want to miss a moment. After all, it's not called the "Happy Valley" for nothing!



Student participation in this conference is partially supported by a grant from the TMS Foundation.



www.mrs.org/EMC2012



Applications Sought for 2012-2013

Congressional Science and Engineering Fellowship

PROGRAM

The Fellow spends one year working as a special legislative assistant on the staff of a member of Congress or congressional committee. Activities may involve conducting legislative or oversight work, assisting in congressional hearings and debates, and preparing briefs and writing speeches. The Fellow also attends an orientation program on congressional and executive branch operations, which includes guidance in the congressional placement process, and a year-long seminar series on science and public policy issues. These aspects of the program are administered by the American Association for the Advancement of Science.

PURPOSE

To provide **Materials Research Society, The Optical Society, and The Minerals, Metals & Materials Society** members with an invaluable public policy learning experience, to contribute to the more effective use of materials and/or optical science knowledge in government, and to broaden awareness about the value of scientist and engineer-government interaction among Society members and within the federal government.

CRITERIA

A prospective Fellow must demonstrate a record of success in research or scholarship, in a field relevant to materials science and technology and/or optical science and technology. The Fellow must also demonstrate sensitivity toward policy issues and have a strong interest in applying

scientific and technical knowledge to U.S. public policy issues. The Fellow must be able to work quickly and communicate effectively on a wide variety of topics, and be able to work cooperatively with individuals having diverse viewpoints. U.S. Citizenship is not required, however, applicants must be authorized to work in the United States.

AWARD

The Fellow will have a one-year appointment beginning September 1, 2012. The Fellowship stipend will be \$72,000 plus assistance for health insurance, travel and relocation expenses to the Washington, DC area. Final selection of the Fellow will be made in early 2012.

APPLICATION

Applications must be postmarked or emailed by January 6, 2012 and must include the following materials: (1) a detailed resume, no longer than two pages, providing information about educational background, professional employment, community and professional activities, public policy and legislative experience and committee and advisory group appointments plus one additional page for professional publications and presentations; (2) a statement of approximately 1,000 words addressing the applicant's interest in the fellowship, career goals, contributions the applicant believes he or she can make as a Fellow to the legislative process and what the applicant wants to learn from the experience; and (3) three signed letters of reference specifically addressing the applicant's ability to work on Capitol Hill as a special legislative assistant.

The deadline for applications is January 6, 2012.

Letters of reference should be mailed or emailed directly by the reference to the appropriate address below and must be in PDF format, on official letterhead, and include an electronic or scanned signature. Letters of reference should not be submitted by the candidates themselves.



MRS/OSA

Congressional Science and Engineering Fellow Program

c/o Laura Kolton
The Optical Society
2010 Massachusetts Avenue, NW
Washington, DC 20036-1023
lkolton@osa.org

Applicant must be a member of MRS or OSA
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For additional information, contact
Laura Kolton at 202-416-1499, lkolton@osa.org
Donna Gillespie at 724-779-2732, gillespie@mrs.org.

MRS/TMS

Congressional Science and Engineering Fellow Program

c/o Donna Gillespie
Materials Research Society
506 Keystone Drive
Warrendale, PA 15086
gillespie@mrs.org

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